

Quiz 1, Time for quiz: max 1 hour Allowed help: Std. mathematical and physical tables, calculator, no internet, no textbook.
The evaluation will be a service only

1.

I'm really looking forward to take this test ☒ (cross mark the politically correct alternative)

2

Cross mark only the correct course code which you register for

☐ FYS4310

☐ FYS9310,

3

Cross mark the correct statement(s) only.

In a CVD reactor for Si epitaxial growth the feed gas is SiCl_2H_2 and H_2 . The feed flow rates are 0.2 l/min and 4 l/min respectively.

The HCl gas concentration in the chamber is proportional to.. **Reaction $\text{SiCl}_2\text{H}_2 + \text{H}_2 = 2 \text{HCl} + \text{SiH}_4$ thus law of mass action**

☐ $[\text{SiCl}_2\text{H}_2]$

☒ $[\text{SiCl}_2\text{H}_2]^{1/2}$

☐ $[\text{SiCl}_2\text{H}_2]^{0.05}$

☐ $[\text{H}_2]^4$

☐ $[\text{SiCl}_2\text{H}_2]^2$

$$\frac{[\text{SiCl}_2\text{H}_2] \cdot [\text{H}_2]}{[\text{HCl}]^2 [\text{SiH}_4]} = K(T) \Rightarrow [\text{HCl}] \propto [\text{SiCl}_2\text{H}_2]^{1/2}$$

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Cross mark the correct statement(s) only

'The energy required to create a Si vacancy (free energy of creation with a net positive charge of one elementary charge is less than that required to create a neutral one' This statement is ..

☐ Never correct for Si ***It can be correct for p-type Si***

☐ Correct for n-type Si ***It is generally not correct for n-type Si***

☐ Always correct for float zone grown Si ***It is not always correct for Si, floatzone or not has very little to do with it***

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Cross mark the correct statement(s) only

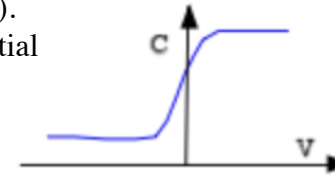
The thermal oxidation growth rate for SiO_2 on Si

☒ is faster for wet oxidation than for dry oxidation because the equilibrium concentration of water molecules are higher than that of oxygen at identical gas pressure. ***In lecture notes we have said its like this, Other reasons have been given***

☐ is increasing exponentially with the doping concentration, ***No from data in book. not even reaction rate it is prop to n?***

6 (* 2210 stuff)

The figure to the right shows a CV curve of a MOS capacitor (Metal-Oxide-Semiconductor). The sign of the voltage is defined as positive when the metal is a positive electrostatic potential with respect to the semiconductor. The graph tell if the semiconductor is n-type or p-type. The doping type of the semiconductor is .



- ☒ n-type *accumulation at positive bias, attract electrons*
- ☐ p-type
- ☐ don't know

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From a CV curves MOS capacitor structures yielding C-V curves like that shown in problem 6 can be used to find.

- ☐ The dielectric constant of Si *NB it say Si, not SiO2,*
- ☒ The area density of charges in the oxide *from the flat band*
- ☐ The break down voltage of the oxide *no, however you will be unable to measure C when reach BV*
- ☐ The elementary charge

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When growing CVD Si at high temperature, the rate limiting mechanism in the growth process is.

- ☐ Step creation
- ☐ Step flow velocity
- ☐ Chemical reaction rate
- ☐ Space charge neutrality
- ☒ Gas transport
- ☐ Space charge neutrality
- ☐ Recombination

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Describe Henry' s law in the space provided before problem 10

Concentration of gas molecules just inside the surface of a material is proportional to the partial pressure just outside the surface

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Consider MBE growth of GaAs. Mark the correct statements only.

- ☐ The growth is typically performed at atmospheric pressure *No, usually UHV*
- ☐ The growth rate (at constant temperature) varies parabolic with time
- ☒ The As vapor pressure is much higher than that of Ga
- ☐ Crystals can be grown fast, but the quality can not be as good as Czochralski grown (bulk) material
- ☒ Surface diffusion of ad atoms occur at the growth temperature.
- ☐ AlAs is grown in a different growth chamber than where GaAs is grown *Usually the same, but of course can be grown in different*
- ☐ MBE is presently the only technique used for growing Mo(molybdenum) doped GaAs. *No Mo doping, Vapor pressure Mo very low,*

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What are the dominant diffusing species during so-called wet oxidation of Si.

- ☒ water
- ☐ silicon
- ☐ oxygen
- ☐ nitrogen
- ☐ vacancies
- ☐ hydrogen and oxygen molecules

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There are many acronyms used throughout the course. Please write the what the following acronyms stands for

- [a] VLSI=Very Large Scale Integration
- [b] MOS = *Metal Oxide Semiconductor*
- [c] CVD = *Chemical Vapor Deposition*
- [d] MBE = *Molecular Beam Epitaxy*
- [e] LPCVD = *Low Pressure Chemical Vapor Deposition (NOT Liquid Phase :-)*
- [f] ALE = *Atomic Layer Epitaxy*
- [g] SLS = *Strained Layer Superlattice*

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Give an order of magnitude answer to these questions

- [a] In 1 cm^3 of GaAs there are 5Exx atoms where $\text{xx} = 22$
- [b] To grow a $1 \mu\text{m}$ thick oxide on Si in steam at 1000°C , we need to grow 1Exx sec, where $\text{xx} = 03$
- [c] The activation energy for vacancy concentration in Si is 2Exx eV where $\text{xx} = 0$
and where the value for the different charge states adds a spread about 1Eyy eV where $\text{yy} = 0.. -1$
- [d] The solid solubility of As in Si at 1100°C is about 1Exx cm^3 where $\text{xx} = 20$
- [e] The bandgap of InAs is about 3Exx eV where $\text{xx} = -1$

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The growth of an epitaxial Si layer in a CVD chamber is diffusion limited, then the instant growth rate dx/dt varies with time as {where k is a parameter independent of t , and x is the thickness}

- ☐ $k*t$
- ☐ $\ln(k*t)$
- ☐ $\exp(-k*t)$
- ☒ k
- ☐ $k*t^{1/2}$

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The segregation coefficient is important for Czochralski growth because

- ☐ The sign indicates whether striations will develop
- ☒ It explains why floatzone technique yields less oxygen
- ☐ It controls nucleation of precipitates in the crystal towards the seed
- ☐ It is zero

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The following statements can be true or false. Check with a cross the statements that are TRUE only

- ☒ This is a test
- ☒ The most common material for the crucible in Czochralskii growth of Si is silica
- ☐ Crystalline Si is too brittle to withstand the processing and handling used for making electronic devices
- ☐ A getter process is done during float Zone growth to get as few vacancies as possible in Si
- ☒ Twins often occur when growing epitaxial Si on wafers with the surface normal along $\langle 111 \rangle$
- ☐ When silicon is exposed to water vapor at 1000 °C, the surface will be covered by silicon monoxide
- ☒ * In silicon the electron mobility in n-type is higher than the hole mobility when the doping concentration is the same in n and p type.
- ☒ In a piece of crystalline Si the room temperature electron mobility is higher than that of the hole in the same material, at all doping concentrations in the range 10^{11} cm^{-3} to 10^{20} cm^{-3} .
- ☐ Vacancies can condense on an atomic plane in a disk like fashion, creating a stacking fault.
The dislocation bounding that stacking fault is called an extrinsic dislocation *it is called intrinsic*
- ☒ The equilibrium vacancy concentration in Si, depends upon the doping concentration
- ☐ The vacancy concentration in Si decreases with increasing temperature as $1/T$.
- ☐ It is fundamentally impossible to grow a dislocation free crystal at a finite temperature

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Which of these denote a polar surface?

- ☐ A cold surface
- ☐ A surface which is biased
- ☐ A surface which is biased positively
- ☐ The surface facing the gas flow in Atomic Layer Deposition
- ☒ A AlAs (111) surface

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When growing GaAs on Si(111) surface, by MBE the first atomic layer is likely to be

- ☐ A (211) layer
- ☐ A Ga layer
- ☐ A 7x7 reconstructed layer
- ☒ An As layer

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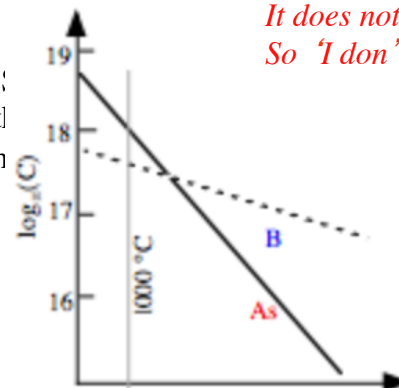
Which of these materials can be called a semiconductor. Mark all that apply!

- ☒ Single crystal Silicon
- ☐ Silica
- ☐ Aluminum saturated with silicon
- ☒ Indium Arsenide doped with Zn
- ☐ Silicon rubber
- ☐ Silane
- ☒ Gallium phosphide at 100 °C
- ☐ Ice
- ☐ Sapphire
- ☐ Tin at 30 °C
- ☒ Zink Selenide
- ☒ Graphene *zero gap semiconductor*

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The figure below shows the solubility of B and A in a *new insulator* in contact with Si as a function of temperature. The Insulator is in contact with regions of Si that is rich in B (boron) and other that are rich in As at the same concentration. When annealing at 1000 °C, which part of the insulator will first reach 10 percent of the solubility limit?

- ☐ That above the A region
- ☐ That above the B region
- ☒ I don't know



*Solubility is an equilibrium property
It does not tell how fast a state is reached
So 'I don't know' is the only correct answer*

